

Search Notes

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10/564,086

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

BIAIS, FRANCOIS

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	214	2/15/2006	HN
310	215	2/15/2006	HN
310	216	2/15/2006	HN
310	52	2/15/2006	HN
310	54	2/15/2006	HN
310	58	2/15/2006	HN
310	64	2/15/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR